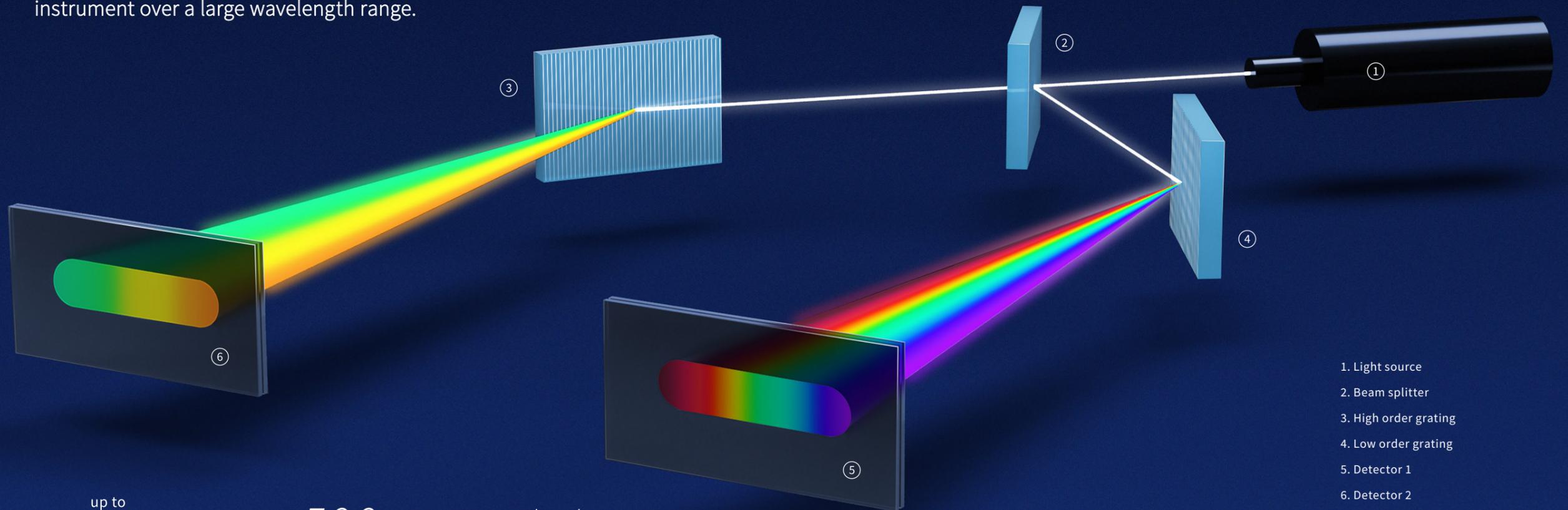


## HighFinesse/Ångstrom Laser Spectrum Analyzer (LSA)

The LSA utilizes an echelle grating and a low order grating in two separate beam paths. The echelle grating provides the LSA with high resolving power, enabling high accuracy measurements. The first order grating makes it possible to overcome the wavelength indeterminacy of the echelle grating.

The combination of both beam paths yields a high resolution instrument over a large wavelength range.



1. Light source
2. Beam splitter
3. High order grating
4. Low order grating
5. Detector 1
6. Detector 2



The LSA can analyze any laser light source (1) regardless if it is cw or pulsed laser and a free beam laser using the included fiber collimators or a fiber laser.

The LSA utilizes an echelle grating (3) and a low order grating (4) in two separate beam paths. The echelle grating provides the LSA with high resolving power, enabling high accuracy measurements. The low order grating makes it

possible to overcome the wavelength indeterminacy of the echelle grating.

The detectors (5) and (6) allow for a high measurement rate with data acquisition up to 500 Hz and a sensitivity down to 0,1 nJ. The LSA comes with a user-friendly and powerful software with a convenient GUI and an API for control of the instrument via your own software.



### Typical Applications

A very common application of our LSA instruments is monitoring the lineshape of lasers during their optical adjustment. With their unmatched measurement speed, our instruments are uniquely suited for this task. In the same way, these instruments can also be used for production certification of laser linewidths and lineshapes.